Search Notes

Application/Control	No	
Application/Control	140.	

Applicant(s)/Patent under Reexamination

NAKAHARA, KEN Art Unit

10/748,734 Examiner

Johannes P. Mondt

2826

	SEARCHED				
Class	Subclass	Date	Examiner		
257	79-103	3/21/2005	JPM		
372	43-50	3/21/2005	JPM		
349	42-53	3/21/2005	JPM		
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INTERFERENCE SEARCHED						
Subclass	Date	Examiner				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East, IEEE, INSPEC	3/21/2005	JPM	